Session 5 Digital Imaging Theories and Novel CT Technologies 数字成像理论与 CT 新技术

14:00-18:10, Saturday, **October 28**, 2023

Location: Room 2-5 (Second Floor) of Great Hall / 会议中心 2-5 会议室

Chair: Jian ZHANG, National Institute of Metrology

Vice-Chair: Xingdong LI, National Institute of Metrology; Yunsong ZHAO, Capital Normal University

Organizer: CT Theory and Application Committee of CSS; National Institute of Metrology

	Title	Reporter	Chairs
14:00-14:10	Opening Ceremony		Xingdong LI
14:10-14:40	The Developments of HEPS and Its Hard X-ray Imaging Beamline	Gang LI, Institute of High Energy Physic, CAS	Li ZHANG, Tsinghua University
14:40-15:00	An Iterative Algorithm for Linear Computed Laminography Based on Recursive Difference	Jing ZOU, Tianjin University	
15:00-15:20	Projection View Selection Based on Error Equi- distribution for Sparse-view CT Reconstruction	Yinghui ZHANG, Capital Normal University	
15:20-15:40	Statistical Iterative Spectral CT Imaging Method Based on Blind Separation of Polychromatic Projections	Xiaojie ZHAO, North University of China	
15:40-16:00	An Image Reconstruction Algorithm for Spectral Exterior Problem Based on Edge-preserving Diffusion and Edge-Preserving Smoothing	Yanwei QIN, Captial Normal University	
16:00-16:10	Tea Break		
16:10-16:30	Metal Artifacts Correction Based on a Physics- informed Nonlinear Sinogram Decomposition Model	Shuqiong FAN, Capital Normal University	Zhanli HU, Shenzhen Institute of Advanced Technology, CAS
16:30-16:50	Noise Power Spectrum of Dark-field Imaging Using a Grating Interferometer	Peiyuan GUO, Tsinghua University	
16:50-17:10	Avoiding Back-projection Weighting Factor for Multiple Source-Translation Computed Tomography Reconstruction	Zhisheng WANG, Harin Institute of Technology	
17:10-17:30	A Random Walk Regularized Smoothing and Inpainting Framework for Depth From Focus	Yuhang ZHENG, Beijing Information Science and Technology University	
17:30-17:50	A Test Method of Maximum Detectable Steel Thickness Based on Industrial X- RAY CT	Haijiang DONG, China United Test & Certification Co., Ltd.	
17:50-18:10	One Kind Direct Conversion X-ray Detector (CdTe Detector)	Dong WANG, Varex Imaging Corporation	

14:00-18:00, Sunday, October 29, 2023

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14:00-14:30	Medical Artificial Intelligence Imaging Based on Medical-industrial Intersection	Zhanli HU, Shenzhen Institute of Advanced Technology, Chinese Academy of Sciences	Min YANG, Beihang University
14:30-14:50	X-RAY Imaging in Cultural Heritage	Qiong XU, Institute of High Energy Physics, CAS	
14:50-15:10	EMCPNN: A Low-dose CT Reconstruction Network Based on TV-regularized EM Algorithm	Ran AN, Capital Normal University	
15:10-15:30	Research on Defect Detection Algorithm for Railway Casting Digital Radiographic Image Based on Deep Learning	Wang LIAO, Chongqing University	
15:30-15:50	A Semi-supervised Denoising Method for Low- dose CT Based on Conditional Normalizing Flow	Chuwen HUANG, Capital Normal University	
15:50-16:00	Tea Break		1
16:00-16:20	Multi-Cost Loss Based Disparity Estimation Network from Light Field	Yuanshen AN, Beijing Information Science and Technology University	Baodong LIU, Institute of High Energy Physic, CAS
16:20-16:40	Research on Dynamic Dual-energy Spectral CT Technology	Huahai SUN, Tsinghua University	
16:40-17:00	TWF-MDTV: Multi-Directional TV algorithm based on the Tight Wavelet Framework for limited-angle CT reconstruction	Jingxue LI, Capital Normal University	
17:00-17:20	A Ring Artifact Removal Model with Dual Domain Regularization for X-ray Computed Tomography	Xin LU, Capital Normal University	
17:20-17:40	Investigation of the Shapes and Distributions of Longhorn Beetles Galleries Using Spiral CT	Rongrong ZHANG, Shandong First Medical University	
17:40-18:00	Static CT, Redefining CT Ultra High Definition Imaging	Jun LIANG, Nanovision Medical Technology (Shanghai) Co., Ltd.	